

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		ATTY. DOCKET NO.	SERIAL NO.
		TI-14124D.6	div. of 10/649,274
		APPLICANT	
		Lee D. Whetsel	
		FILING DATE	GROUP
		October 22, 2003	TBD
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			
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EXAMINER <i>C. Butt</i>		DATE CONSIDERED <i>4-25-03</i>	

+EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER <i>C. Batt</i>	DATE CONSIDERED <i>4-25-05</i>				

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